

November 2012

# FSA3031 — Dual High-Speed USB2.0 with Mobile High-Definition Link (MHL<sup>™</sup>)

## Features

- Low On Capacitance: 4.6 pF/6.75 pF MHL/USB (Typical)
- Low Power Consumption: 30 µA Maximum
- Supports MHL Rev. 2.0

SEMICONDUCTOR

- Passes 1080 p/60 fps (3 Gbps) MHL Data Eye Diagram Mask Compliance
- MHL Data Rate: ≥4.7Gbps with Ideal Input Source
- Packaged in 12-Lead UMLP (1.8 x 1.8 mm)
- Over-Voltage Tolerance (OVT) on all USB Ports Up to 5.25 V without External Components

### **Applications**

Cell Phones and Digital Cameras

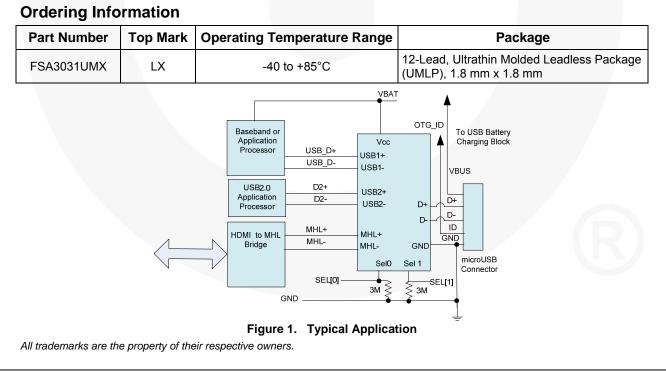
#### **IMPORTANT NOTE:**

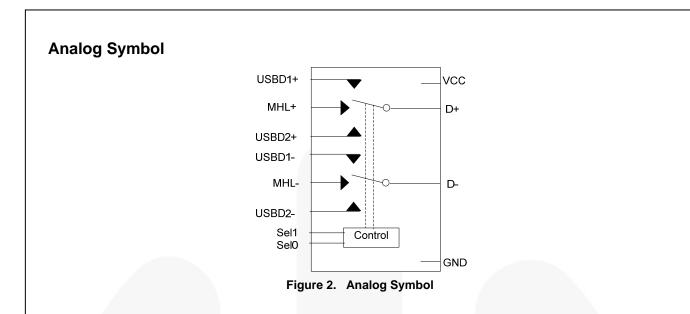
For additional performance information, please contact <u>interface@fairchildsemi.com</u>.

#### Description

The FSA3031 is a bi-directional, low-power, high-speed, 3:1, dual USB2.0 and MHL switch. Configured as a double-pole, triple-throw (DP3T) switch; it is optimized for switching between dual high- or full-speed USB and Mobile High-Definition Link sources (MHL<sup>™</sup> Rev. 2.0 specification).

The FSA3031 contains special circuitry on the switch I/O pins, for applications where the  $V_{CC}$  supply is powered off ( $V_{CC}$ =0), that allows the device to withstand an over-voltage condition. This switch is designed to minimize current consumption even when the control voltage applied to the control pins is lower than the supply voltage ( $V_{CC}$ ). This feature is especially valuable to mobile applications, such as cell phones; allowing direct interface with the general-purpose I/Os of the baseband processor. Other applications include switching and connector sharing in portable cell phones, digital cameras, and notebook computers.



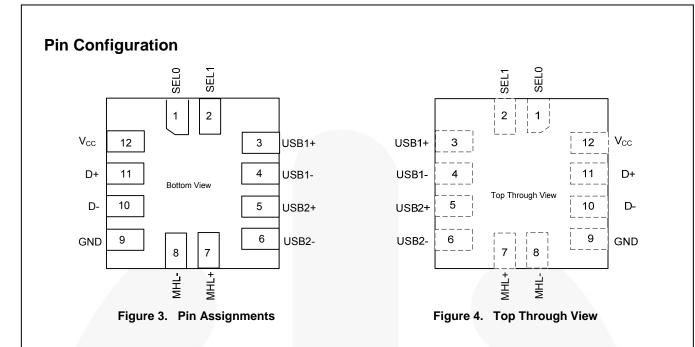


#### Table 1. Data Switch Select Truth Table

SEL1 <sup>(1)</sup>	SEL0 <sup>(1)</sup>	Function
0	0	D+/D- connected to USB1+/USB1-
0	1	D+/D- connected to USB2+/USB2-
1	0	D+/D- connected to MHL+/MHL
1	1	D+/D- high impedance

Note:

Control inputs should never be left floating or unconnected. To guarantee default switch closure to the USB position, the SEL[0:1] pins should be tied to GND with a weak pull-down resistor (3 MΩ) to minimize static current draw.



## **Pin Definitions**

Pin#	Name	Description
1	SEL0	Data Switch Select
2	SEL1	Data Switch Select
3	USB1+	USB Differential Data (Positive) – Source 1
4	USB1-	USB Differential Data (Negative) – Source 1
5	USB2+	USB Differential Data (Positive) – Source 2
6	USB2-	USB Differential Data (Negative) – Source 2
7	MHL+	MHL Differential Data (Positive)
8	MHL-	MHL Differential Data (Negative)
9	GND	Ground
10	D-	Data Switch Output (Positive)
11	D+	Data Switch Output (Negative)
12	V <sub>CC</sub>	Device Power from System

## **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter		Min.	Max.	Unit
V <sub>CC</sub>	Supply Voltage			6.0	V
V <sub>CNTRL</sub>	DC Input Voltage (SEL[1:0]) <sup>(2)</sup>		-0.5	V <sub>CC</sub>	V
V <sub>SW</sub> <sup>(3)</sup>	DC Switch I/O Voltage <sup>(2)</sup>	USB	-0.50	Vcc	V
V <sub>SW</sub> `´	DC Switch I/O Voltage	MHL	-0.50	V <sub>CC</sub>	
I <sub>IK</sub>	DC Input Diode Current		-50		mA
		USB		60	mA
I <sub>OUT</sub>	Switch DC Output Current (Continuous)	MHL		60	mA
1	Switch DC Output Peak Current	USB		150	mA
IOUTPEAK	(Pulsed at 1m Duration, <10% Duty Cycle)	MHL		150	mA
T <sub>STG</sub>	Storage Temperature		-65	+150	°C
MSL	Moisture Sensitivity Level (JEDEC J-STD-020A)			1	
	Human Body Model, JEDEC: JESD22-A114 All Pins			4	
FOD	IEC 61000-4-2, Level 4, for D+/D- and V <sub>CC</sub> Pins <sup>(4)</sup>			8	
ESD	IEC 61000-4-2, Level 4, for D+/D- and V <sub>CC</sub> Pins <sup>(4)</sup> Air			15	kV
	Charged Device Model, JESD22-C101	-		2	

Notes:

2. The input and output negative ratings may be exceeded if the input and output diode current ratings are observed.

- 3. V<sub>SW</sub> refers to analog data switch paths (USB1, MHL, and USB2).
- 4. Testing performed in a system environment using TVS diodes.

## **Recommended Operating Conditions**

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to Absolute Maximum Ratings.

Symbol	Parameter	Min.	Max.	Unit
V <sub>CC</sub>	Supply Voltage	2.5	4.5	V
t <sub>RAMP(VCC)</sub>	Power Supply Slew Rate	100	1000	μs/V
$\Theta_{JA}$	Thermal Resistance		230	C°/W
V <sub>CNTRL</sub>	Control Input Voltage (SEL[1:0]) <sup>(5)</sup>	0	4.5	V
V <sub>SW(USB)</sub>	Switch I/O Voltage (USB1/USB2 Switch Paths)	-0.5	3.6	V
V <sub>SW(MHL)</sub>	Switch I/O Voltage (MHL Switch Path)	1.65	3.45	V
T <sub>A</sub>	Operating Temperature	-40	+85	°C

Note:

5. The control inputs must be held HIGH or LOW; they must not float.

## **DC Electrical Characteristics**

All typical values are at  $T_A=25^{\circ}C$  unless otherwise specified.

0			<u> </u>	T <sub>A</sub> =- 40°C to +85°C			
Symbol	Parameter	Condition	V <sub>cc</sub> (V)	Min.	Тур.	Max.	Unit
VIK	Clamp Diode Voltage	I <sub>IN</sub> =-18 mA	2.5			-1.2	V
V <sub>IH</sub>	Control Input Voltage, High SEL[1:0]		2.5 to 4.5	1.0			V
VIL	Control Input Voltage, Low SEL[1:0]		2.5 to 4.5			0.5	V
I <sub>IN</sub>	Control Input Leakage, SEL[1:0]	$V_{SW}$ =0 to 3.6 V, $V_{CNTRL}$ =0 to $V_{CC}$	4.5	-0.5		0.5	μA
I <sub>OZ(MHL)</sub>	Off-State Leakage for Open MHL Data Paths	V <sub>SW</sub> =1.65≤ MHL ≤ 3.45 V,SEL[1:0]=V <sub>CC</sub>	4.5	-0.5		0.5	μA
I <sub>OZ(USB)</sub>	Off-State Leakage for Open USB Data Paths	$\label{eq:V_SW} \begin{array}{l} V_{SW} \texttt{=} \texttt{0} \leq USB {\leq} 3.6 \; V, \\ SEL[1:0] \texttt{=} V_{CC} \end{array}$	4.5	-0.5		0.5	μA
I <sub>CL(MHL)</sub>	On-State Leakage for Closed MHL Data Paths <sup>(6)</sup>	$\label{eq:sws} \begin{array}{l} V_{SW} \mbox{=} 1.65 \mbox{\leq} \ \mbox{MHL} \mbox{\leq} 3.45 \ \mbox{V}, \\ \mbox{SEL0} \mbox{=} \mbox{GND}, \ \mbox{SEL1} \mbox{=} V_{CC}, \ \mbox{Other} \\ \mbox{Side of Switch Float} \end{array}$	4.5	-0.5		0.5	μA
I <sub>CL(USB)</sub>	On-State Leakage for Closed USB Data Paths <sup>(6)</sup>	$\label{eq:sws} \begin{array}{l} V_{SW} = 0 \leq USB \leq 3.6 \ V \\ SEL[1:0] = GND \ or \ SEL1 = GND, \\ SEL0 = V_{CC}, \ Other \ Side \ of \\ Switch \ Float \end{array}$	4.5	-0.5		0.5	μA
IOFF	Power-Off Leakage Current (All I/O Ports)	V <sub>SW</sub> =0 V or 3.6 V, Figure 5	0	-0.5		0.5	μA
R <sub>ON(USB)</sub>	HS Switch On Resistance (USB to D Path)	V <sub>SW</sub> =0.4 V, I <sub>ON</sub> =-8 mA SEL[1:0]=GND or SEL1=GND, SEL0=V <sub>CC</sub> , Figure 6	2.5		3.9	6.5	Ω
R <sub>ON(MHL)</sub>	HS Switch On Resistance (MHL to D Path)	$V_{SW}$ = $V_{CC}$ -1050 mV, SEL0=GND, SEL1= $V_{CC}$ , $I_{ON}$ =-8 mA, Figure 6	2.5		5		Ω
$\Delta R_{ON(MHL)}$	Difference in R <sub>ON</sub> Between MHL Positive-Negative	$V_{SW}$ =V <sub>CC</sub> -1050 mV, SEL0=GND, SEL1=V <sub>CC</sub> , I <sub>ON</sub> =-8 mA, Figure 6,	2.5		0.03		Ω
$\Delta R_{ON(USB)}$	Difference in R <sub>ON</sub> Between USB Positive-Negative	$V_{SW}$ =0.4 V, I <sub>ON</sub> =-8 mA, SEL[1:0]=GND or SEL1=GND, SEL0=V <sub>CC</sub> Figure 6	2.5		0.22		Ω
R <sub>ONF(MHL)</sub>	Flatness for R <sub>ON</sub> MHL Path	$V_{SW}$ =1.65 to 3.45 V, SEL0=GND, SEL1=V_{CC}, $I_{ON}$ =-8 mA, Figure 6	2.5		1		Ω
I <sub>CC</sub>	Quiescent Current	$V_{CNTRL}$ =0 or 4.5 V, I <sub>OUT</sub> =0	4.5			30	μA
I <sub>CCT</sub>	Delta Increase in Quiescent	V <sub>CNTRL</sub> = 1.65 V, I <sub>OUT</sub> =0	4.5			18	μA
-001	Current per Control Pin	$V_{CNTRL}$ = 2.5 V, $I_{OUT}$ =0	4.5			10	μ.,

#### Note:

6. For this test, the data switch is closed with the respective switch pin floating.

FSA3031 — Dual High-Speed USB2.0 Switch with Mobile High-Definition Link (MHL<sup>™</sup>) Switch

## AC Electrical Characteristics

Symbol	Demonster	Que d'élan		T <sub>A</sub> =- 40°C to +85°C			11
Symbol	Parameter	Condition	V <sub>cc</sub> (V)	Min.	Тур.	Max.	Unit
tonusb	USB Turn-On Time, SEL[1:0] to Output $R_L=50 \Omega$ , $C_L=5 pF$ , $V_{SW(USB)}=0.8 V$ , $V_{SW(MHL)}=3.3 V$ , Figure 7, Figure 8		2.5 to 3.6		445	600	ns
t <sub>OFFUSB</sub>	USB Turn-Off Time, SEL[1:0] to Output	$\begin{array}{l} R_{L}\text{=}50 \ \Omega, \ C_{L}\text{=}5 \ pF, \ V_{SW(USB)}\text{=}0.8 \ V, \\ V_{SW(MHL)}\text{=}3.3 \ V, \ Figure \ 7, \ Figure \ 8 \end{array}$	2.5 to 3.6		445	600	ns
t <sub>onmhl</sub>	MHL Turn-On Time, SEL[1:0] to Output	$R_L$ =50 $\Omega, C_L$ =5 pF, $V_{SW(USB)}$ =0.8 V, $V_{SW(MHL)}$ =3.3 V, Figure 7, Figure 8	2.5 to 3.6		445	600	ns
t <sub>OFFMHL</sub>	MHL Turn-Off Time, SEL[1:0] to Output	$\begin{array}{l} R_{L} = 50 \ \Omega, \ C_{L} = 5 \ pF, \ V_{SW(USB)} = 0.8 \ V, \\ V_{SW(MHL)} = 3.3 \ V, \ Figure \ 7, \ Figure \ 8 \end{array}$	2.5 to 3.6		445	600	ns
t <sub>PD</sub>	Propagation Delay <sup>(7)</sup>	$C_L$ =5 pF, $R_L$ =50 $\Omega$ , Figure 7, Figure 9	2.5 to 3.6		0.25		ns
t <sub>BBM</sub>	Break-Before-Make Time <sup>(7)</sup>	$R_L{=}50~\Omega,~C_L{=}5~pF,~V_{ID}{=}V_{MHL}{=}3.3~V,~V_{USB}{=}0.8~V,~Figure~11$	2.5 to 3.6		85		ns
O <sub>IRR(MHL)</sub>	Off Isolation <sup>(7)</sup>	$V_S$ =1 $V_{pk-pk}$ , $R_L$ =50 $\Omega$ , f=240 MHz, Figure 12	2.5 to 3.6		-41		dB
O <sub>IRR(USB)</sub>	On Isolation ?	V <sub>S</sub> =400 mV <sub>pk-pk</sub> , R <sub>L</sub> =50 Ω, f=240 MHz, Figure 12	2.5 to 3.6		-36		dB
Xtalk <sub>MHL</sub>	Non-Adjacent	$V_S$ =1 $V_{pk-pk}$ , $R_L$ =50 $\Omega$ , f=240 MHz, Figure 13	2.5 to 3.6		-41		dB
Xtalk <sub>USB</sub>	Channel <sup>(7)</sup> Crosstalk	V <sub>S</sub> =400 mV <sub>pk-pk</sub> , R <sub>L</sub> =50 Ω, f=240 MHz, Figure 13	2.5 to 3.6		-37		dB
BW Differential -3db Bandwidth <sup>(7)</sup>	Differential -3db	$V_{IN}$ =1 $V_{pk-pk}$ , MHL Path, Common Mode Voltage = $V_{CC}$ – 1.1 V, R <sub>L</sub> =50 $\Omega$ , C <sub>L</sub> =0 pF, Figure 14	25 to 26		1.87		CH-
		$V_{IN}$ =400 mV <sub>pk-pk</sub> , USB Path, Common Mode Voltage = 0.2 V, R <sub>L</sub> =50 Ω, C <sub>L</sub> =0 pF, Figure 14	2.5 to 3.6		1.47		GHz

All typical values are for V<sub>CC</sub>=3.3 V and T<sub>A</sub>=25°C unless otherwise specified.

Note:

7. Guaranteed by characterization.

## **USB High-Speed AC Electrical Characteristics**

Typical values are at  $T_A$ = -40°C to +85°C.

Symbol	Parameter	Condition	V <sub>cc</sub> (V)	Тур.	Unit
t <sub>SK(P)</sub>	Skew of Opposite Transitions of the Same Output <sup>(8)</sup>	$C_L$ =5 pF, R <sub>L</sub> =50 $\Omega$ , Figure 9	3.0 to 3.6	7	ps
tJ	Total Jitter <sup>(8)</sup>	R <sub>L</sub> =50 Ω, C <sub>L</sub> =5 pF, t <sub>R</sub> =t <sub>F</sub> =500 ps (10-90%) at 480 Mbps, PN7	3.0 to 3.6	18	ps

Note:

8. Guaranteed by characterization.

## **MHL AC Electrical Characteristics**

Typical values are at  $T_A$ = -40°C to +85°C.

Symbol	Parameter	Condition	V <sub>cc</sub> (V)	Тур.	Unit
t <sub>SK(P)</sub>	Skew of Opposite Transitions of the Same Output <sup>(9)</sup>	$R_{PU}$ =50 $\Omega$ to $V_{CC}$ , $C_L$ =0 pF	3.0 to 3.6	3	ps
tJ	Total Jitter <sup>(9)</sup>	f=2.25 Gbps, PN7, $R_{PU}$ =50 $\Omega$ to $V_{CC}$ , $C_L$ =0 pF	3.0 to 3.6	23	ps

Note:

9. Guaranteed by characterization.

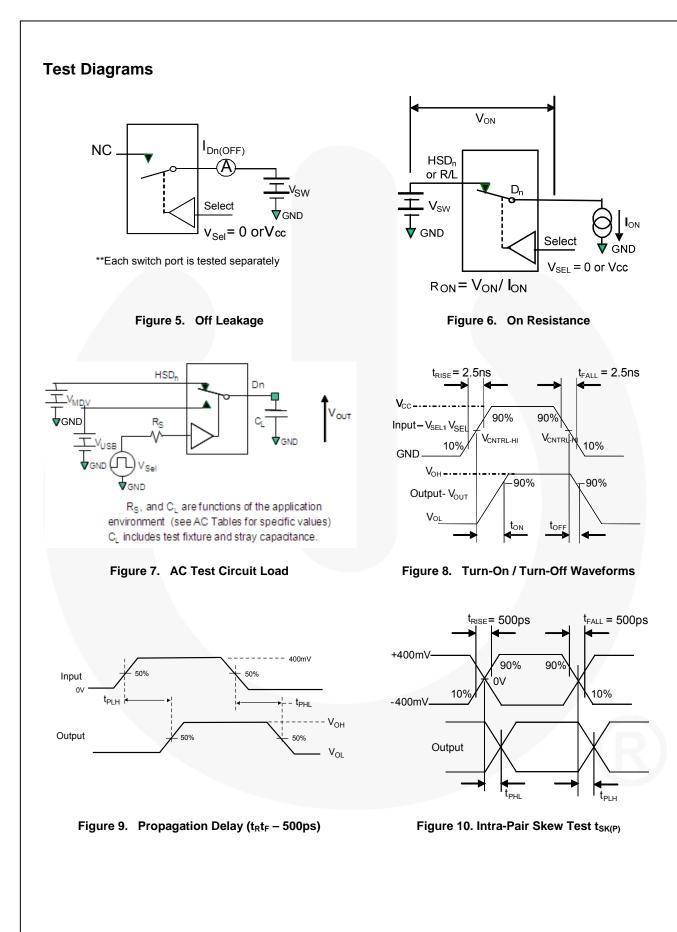
## Capacitance

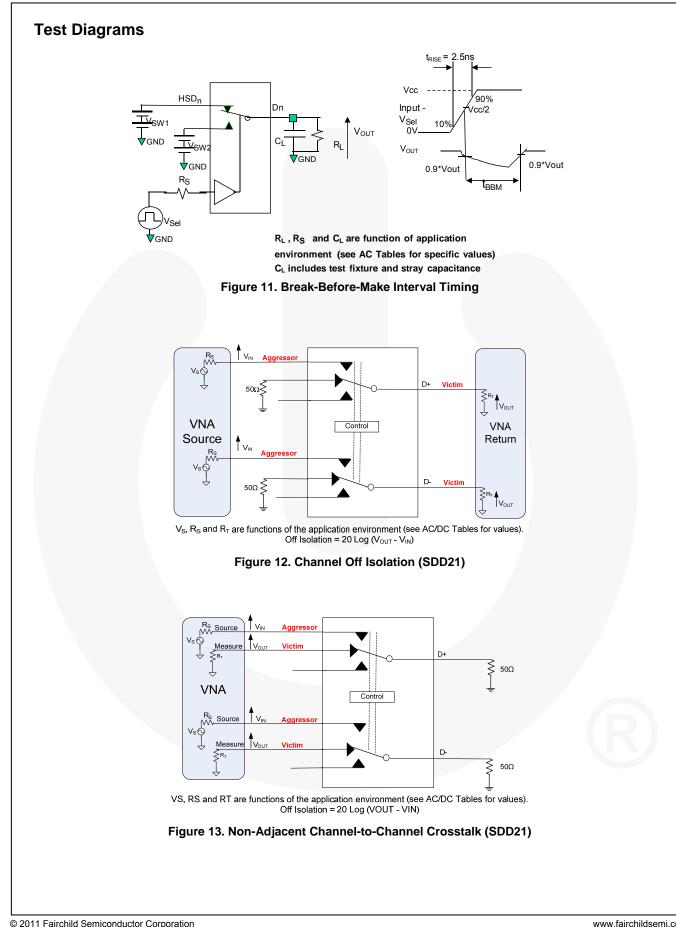
Typical values are at  $T_A$  = -40°C to +85°C.

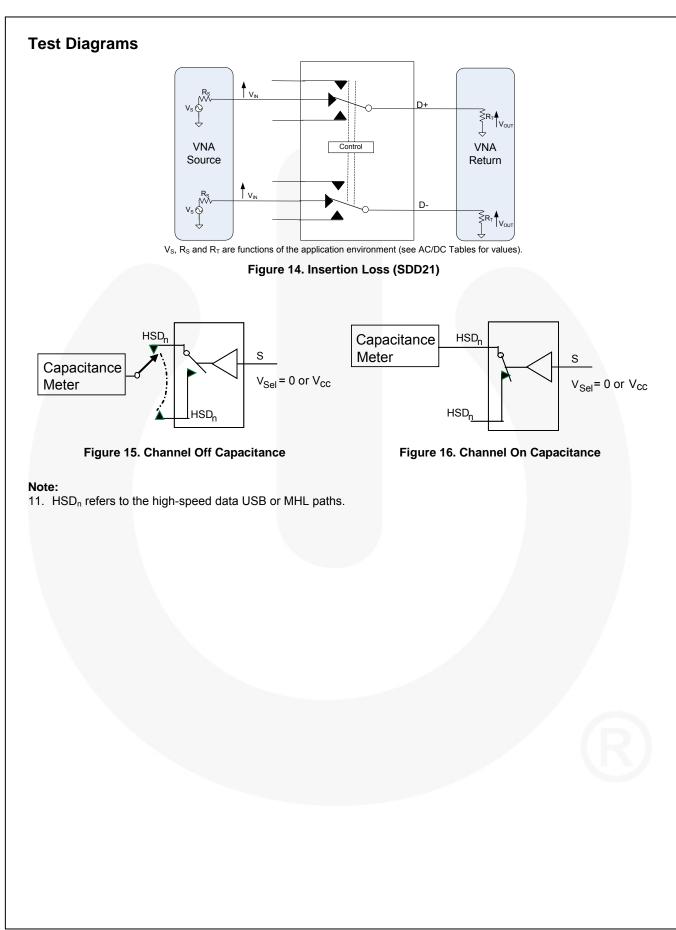
Symbol	Parameter	Condition	Тур.	Max.	Unit
CIN	Control Pin Input Capacitance <sup>(10)</sup>	V <sub>CC</sub> =0 V, f=1 MHz	2.5		pF
C <sub>ON(USB)</sub>	USB Path On Capacitance <sup>(10)</sup>	V <sub>CC</sub> =3.3 V, f=240 MHz, Figure 15	6.75		pF
C <sub>OFF(USB)</sub>	USB Path Off Capacitance <sup>(10)</sup>	V <sub>CC</sub> =3.3 V, f=240 MHz, Figure 13	2.5		pF
CON(MHL)	MHL Path On Capacitance <sup>(10)</sup>	V <sub>CC</sub> =3.3 V, f=240 MHz, Figure 15	4.6		pF
C <sub>OFF(MHL)</sub>	MHL Path Off Capacitance <sup>(10)</sup>	V <sub>CC</sub> =3.3 V, f=240 MHz, Figure 13	2.5		pF

Note:

10. Guaranteed by characterization.







FSA3031 — Dual High-Speed USB2.0 Switch with Mobile High-Definition Link (MHL<sup>™</sup>) Switch

#### **Insertion Loss**

One of the key advantages of using the FSA3031 in mobile digital video applications is the small amount of insertion loss experienced by the received signal as it passes through the switch.

This results in minimal degradation of the received eye. One of the ways to measure the quality of the high data rate channels is using balanced ports and four-port differential S-parameter analysis, particularly SDD21.

Bandwidth is measured using the S-parameter SDD21 methodology. Figure 17 exhibits the 1.87 GHz (-3 db) BW of the MHL path, while Figure 18 exhibits the 1.47 GHz (-3 db) BW of the USB paths.

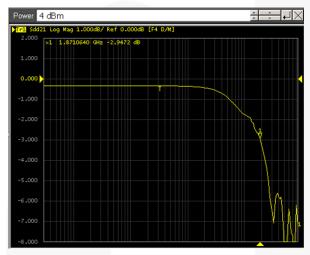






Figure 18. USB Path SDD21 Insertion Loss Curve

## **Typical Application**

Figure 19 shows utilizing the VBAT connection from the micro-USB connector. The 3M resistors are used to ensure, for manufacturing test via the micro-USB connector, that the FSA3031 configures for connectivity to the baseband or application processor.

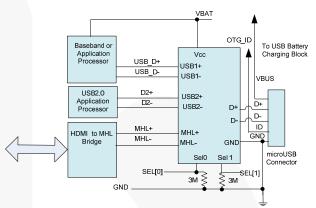
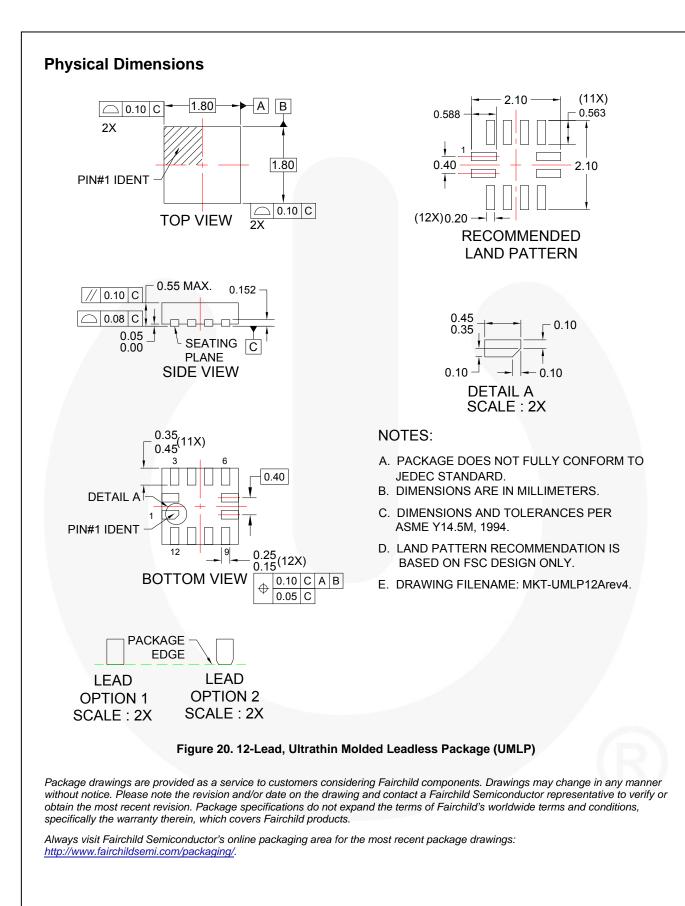


Figure 19. Typical Application



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